Decoherence processes in a current biased dc SQU ID

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A current bias dc SQ U ID behaves as an anham onic quantum oscillator controlled by a bias current and an applied m agnetic ux. We consider here its two level lim it consisting of the two lower energy states ju and jli. We have measured energy relaxation times and microwave absorption for dierent bias currents and uxes in the low microwave power limit. Decoherence times are extracted. The low frequency ux and current noise have been measured independently by analyzing the probability of current switching from the superconducting to the nite voltage state, as a function of applied ux. The high frequency part of the current noise is derived from the electrom agnetic environment of the circuit. The decoherence of this quantum circuit can be fully accounted by these current and ux noise sources.

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In the past years, coherent manipulation of two and multi-level quantum systems, e cient quantum readouts, entanglem ent between quantum bits have been achieved [1, 2, 3, 4, 5, 6] dem onstrating the full potential of quantum logic in solid state physics. At present, future developments require longer coherence times [8, 9, 10]. In contrast with atom ic system, the huge number of degree of freedom makes its optimization a challenging problem . Up to now, the most successful strategy has been to manipulate the quantum system at particular working points where its coupling to external noise is m inim al[2]. Nevertheless, experim ental analysis of decoherence phenom ena in superconducting circuits rem ains a priority for a full-control of quantum experim ents. D ifferent models for the noise sources have been proposed to describe the decoherence processes acting on various qubits [7, 8, 9, 10]. How ever a com plete and consistent understanding of decoherence remains a current and open problem . In this paper, we study decoherence processes of a phase qubit: the current biased dc SQUD.

This superconducting circuit consists of two Josephson junctions (JJ), each with a critical current I_0 and a capacitance C₀. The junctions are embedded in a superconducting loop of inductance L_s , threaded by a ux b. In the lim it where $L_s I_0$ $_0=2$, the phase dynam ics of the two junctions can be mapped onto a ctitious particle following a one dimensional path in a 2D-potential [5]. If the biasing current I_b is smaller than the SQUID critical current I_c, the particle is trapped in a cubic potential well characterized by its bottom frequency $!_{p}(I_{b}; b)$ and a barrier height $U(I_b; b)$ (Fig. 1.a). The quantum states in this anham onic potential are denoted jni, with corresponding energies E_n , n = 0;1; ... In the following, only the low est states pi and ji will be involved. For L well below I_c, these two levels are stable and constitute a phase qubit.

W hen the bias current $I_{\rm b}$ is close to $I_{\rm c}$, U decreases and becomes of the order of a few ~!_p. The ground state can tunnel through the potential barrier and the SQUID switches to a voltage state[11]. The tunnelling rate $_0$ of the ground state jDi is given by

the well-known MQT formula for underdam ped JJ[12]: $_0$ (I_b; _b) = a!_p exp(36 U=5~!_p), where a is of order unity.

The environm ent of the dc SQ U ID induces uctuations of the bias current and the bias ux. In this work, we show how the current and ux noise sources can be separately quanti ed. This is achieved by escape m easurem ents of the SQ U ID at speci c working points where it is mostly sensitive to current or ux noise. U sing these identi ed noise sources, the m easured decoherence tim es are t precisely as a function of bias current.

Experimental results are analyzed assuming a linear coupling between the SQUID and the environment degrees of freedom. We suppose that current ^CI and ux ^C noises are generated by independent gaussian sources. Here, C_x (x = I or) is an operator acting on the environment. Their uctuations are specifed by the quantum spectral densities S_x ()[14]. In presence of ux m icrowave (MW) excitation, the total Ham iltonian IP in the SQUID eigenstates basis fjDi; jLig reads: ı₽ = $\frac{1}{2}h_{01}b_z$ $h_R \cos(2 t)b_x + N^0$ where b_x and b_z are Paulim atrices and $_{01} = (E_1 \quad E_0) = h \cdot T he$ rst term is the qubit Ham iltonian and the second term describes the MW excitation of reduced amplitude $_{\rm R}$ at frequency . In this notation, $_{\rm R}$ is also the Rabi precession frequency for a tuned excitation $(=_{01})$. The last term is the coupling to the noise sources. For our circuit it is, within linear response,

$$\Phi = \frac{h}{2} b_{x} \frac{h}{2} \frac{r_{I}()}{p_{C_{0}h_{01}}} c_{I} + \frac{r}{L_{s}} \frac{()}{c_{0}h_{01}} c_{I} + \frac{h}{2} b_{z} \frac{h}{q_{0}} \frac{q_{01}}{q_{1}} c_{I} + \frac{q_{01}}{q_{0}} c_{I} + \frac{q_{01}}{q_{0}}$$

where is the asymmetry inductance parameter (see below), $r_{\rm I}() = \cos + \sin , r() = \sin$ and is the angle between the escape and the mean slope directions in the 2D potential[11, 15]. To rst order, the transverse noise proportional to b_x only induces depolarization. The longitudinal term proportional to b_z induces "pure" dephasing. The qubit sensitivity to

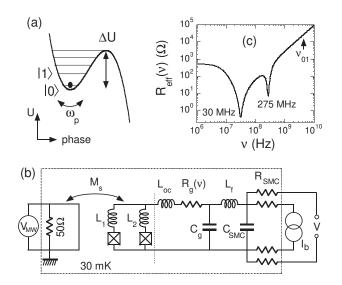


FIG. 1: (a) Squid cubic-quadratic potential. (b) E lectrical environm ent of the SQUID. (c) Calculated e ective real im pedance R_{eff} versus frequency.

longitudinal noise is given by the partial derivatives (@ $_{01}=@I_b$) and (@ $_{01}=@I_b$). They depend strongly on the experim ental working point and increase near the critical current.

The measured SQUID consists of two large alum inum JJs of 15 m 2 area (I_0 = 1:242 A and C_0 = 0:56 pF) enclosing a 350 m²-area superconducting loop. The two SQUD branches of inductances L_1 and L_2 contribute to the total loop inductance $L_s = 280 \, \text{pH}$ with the asym m etry parameter = $(L_1 \quad L_2)=L_s = 0.414$. The immediate electrom agnetic environm ent of the SQUID is designed to decouple the circuit from the external world. It consists of two cascaded LC lters (see Fig. 1.b). A large onchip inductance $L_{oc} = 9 n H$ is made of two long and thin superconducting wires which value, derived from the norm al state resistance, is dom inated by the kinetic inductance. The gold thin Im parallel capacitor, C_q 150pF, introduces a nite resistor. Its dc value at 30 m K is $R_g = 0.1$ giving the gold resistivity $g = 1.210^8$ m. The second lter consists of the bounding wires, with an estim ated inductance $L_f = 3 nH$, and a surface m ounted (SM C) capacitor $C_{SM C} = 2nF$ and four 500 SM C resistors. The nom inal room tem perature microwave signal is guided by 50 coaxial lines, attenuated at low tem perature before reaching the SQUID through a mutual inductance $M_s = 1.3 \, \text{pH}$. Special care was taken in magnetic shielding and bias lines Itering. All these electrical param eters were determ ined independently [11, 13]. Our environm ent model predicts two resonances (resistance dips in Fig. 1.c). They were observed in a similar set-up and the associated resonance frequencies were in precise agreem ent with the model.

The current noise through the SQUID com es mostly from its immediate environment thermalized at T =

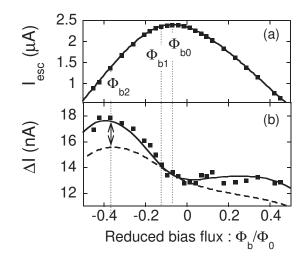


FIG.2: (a) M easured escape current (dots) versus external applied ux tted to MQT theory (solid line) at 30 mK. (b) The width of the probability distribution $P_{\rm esc}$ ($I_{\rm b}$) (dots) tted to the 2D MQT predictions. The solid curve takes the low frequency ux noise into account while the dashed line does not. At bias ux $_{\rm b0}$ (resp. $_{\rm b1}$) the sensitivity to ux noise is zero (resp. sm all) while it is maximum at $_{\rm b2}$.

 $30\,\text{mK}$ ($_{\text{T}}$ $k_B T = h = 600 M H z$ $_{01}$). The quantum spectral density of the current noise, S_{I} () in this environm ent is set by the uctuation-dissipation theorem : $S_{I}() = h \operatorname{coth} \frac{h}{2k_{B}T} + 1 R_{e} ()^{1} \text{ where } R_{e} ()^{1}$ is the real part of the environm ent circuit adm ittance. R_e () is calculated using the electrical circuit shown in Fig. 1 b and is plotted in Fig. 1.c. To a good approxim ation, the root m ean square (RMS) current uctuations are of order $k_B T = L_{oc} = 6 nA$. Most of the noise is peaked around 30 M H z, a frequency much sm aller than $_{\rm T}$. A simple estimate of the ux noise produced by the inductive coupling to the 50 coaxial line shows it can be neglected in the following.

The escape probability $P_{esc}\left(I_{b}\right)$ out of the superconducting states is measured at xed ux using dc current pulses with t = 50 s duration and I $_{b}$ amplitude. Each measurement involves 5000 identical current pulses and the total acquisition time is T_{m} = 10 s. The escape current I_{esc} is de ned as the current I_{b} where the escape probability $P_{esc}\left(I_{b}\right) = 0$:5 and the width of the switching curve I = I $_{h}$ I as the difference between the currents where $P_{esc}\left(I_{h}\right) = 0$:9 and $P_{esc}\left(I_{l}\right) = 0$:1. In Fig. 2, the dependence of I_{esc} and I on $_{b}$ are plotted. By thing the escape current curve $I_{esc}\left({}_{b}\right)$, the experimental parameters of the SQUID $\left(I_{0};C_{0};L_{s};\right)$ are determined.

M oreover, escape m easurem ents are a sensitive tool to characterize noise (frequency range and am plitude). If noise frequencies exceed the inverse of a current pulse duration t⁻¹, the tunnel rate uctuates during each current pulse. The escape probability is controlled by the average $_0$ escape rate in the frequency window [t⁻¹, T]: P_{esc} = 1 exp $_0$ I_b + I; b + t [11, 16]. The current noise produced by the electrical

environm ent lies in this frequency interval. Its e ect is to decrease $I_{esc}(_{b})$ by about 6 nA, the RMS current uctuations (unobservable in Fig. 2*a*). Similarly, the width of the switching curve is not a ected.

On the other hand, if noise frequencies are slower than t ¹, the tunnel rate is constant during a pulse, but uctuates from pulse to pulse. In this lim it, the escape probability becomes $P_{esc} = 1$ exp ₀ I_b + I; _b + t, where the statistical average is now in frequency range from T_m^{-1} to t 1 . To rst order, low frequency noise does not a ect I_{esc} , but increases the width I. Thus I is the best quantity to probe the origin and the magnitude of the low frequency uctuations: if the ux $_{\rm b}$ is set at the value $_{
m b0}$ which maximizes I $_{
m c}$, the SQUD is only sensitive to current uctuations since $\frac{a}{a} = 0$. In the vicinity of this ux, the measured width is explained by the usual MQT theory. Hence the measured RMS current uctuations in the $[T_m^{-1}, t^{-1}]$ interval (low frequency current noise) is below 0:5 nA, the error bar in I measurements. This is consistent with the 0:1 nA RMS value derived from the spectral density of noise at frequencies below t¹. For other applied uxes, the width is slightly larger than MQT prediction, indicating a residual low frequency ux noise. The dependence of I on b shown in Fig. 2 b is perfectly explained by a gaussian low frequency ux noise. Its RMS $^{2}_{LF}$ = 5:5 10^{4}_{0} , is extracted from am plitude, the t shown in Fig. 2 b and is attributed to the ux noise in the [100 m H z; 20 kH z] frequency interval. The origin of ux noisem ay be due to vortices trapped in the four alum inum contact pads located at a 0:5mm distance from the SQUD.

Hereafter we discuss dephasing and relaxation induced by the noise sources previously identi ed. These incoherent processes are experimentaly studied with low power spectroscopy and energy relaxation m easurem ent. A s described in Ref. [5], a M W ux pulse is applied followed by a 2 ns duration dc ux pulse to perform a fast but adiabatic measurement of the quantum state of the SQU D (Fig. 3.c inset). The duration $T_{M W} = 300 \text{ ns of } M W$ pulses is su cient to reach the stationnary state where the population p_1 of the level jli only depends on and the amplitude $_{\rm R}$. The microwave amplitude $_{\rm R}$ is calibrated using Rabi like oscillations [5]. In the two level experiments discussed in this paper, the measured escape probability Pesc induced by the dc ux pulse can be interpreted as $P_{esc} = P_{esc}^{jli} + (P_{esc}^{jli})$ Pesc) р(;_R). $P_{\rm esc}^{\,j_{\rm n}\,i}$ denotes the escape probability out of the pure state jni. In Fig. 3 a and 3 b, the escape probability versus m icrowave frequency are plotted at two di erent biasing points. The experim ental curves present a resonant peak which position and full width at half maximum dene the resonant frequency $_{01}$ and . Spectroscopy experiments are performed in the linear regime and is experim entally checked to be independent of the MW am plitude. Relaxation measurements were performed by

populating the jlistate with low powerMW tuned at 01

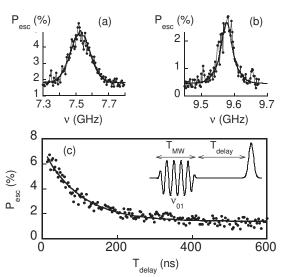


FIG. 3: (a) and (b) Escape probability versus applied microwave frequency with amplitude $_{\rm R}$ < 5 MHz at two different working points ($\rm I_b$ = 2.288 A; $_{\rm b1}$ = 0.117 $_0$) and ($\rm I_b$ = 0.946 A; $_{\rm b2}$ = 0.368 $_0$), respectively. The points are experimental data and the continuous lines are the Fourier transform soff_{coh} (t) (see text). (c) M easured escape probability versus delay time (dots) tted to an exponential law with T_1 = 95 ns (continuous line). The inset speci es the tim ing of the measurement pulse which follows the MW excitation pulse.

during a time $T_{M W} = 300 \text{ ns}$, and measuring its population with increasing time delay T_{delay} after the end of the MW pulse. As shown in Fig. 3.c, the escape probability follows an exponential relaxation with a characteristic time T_1 . In Fig. 4, measured resonant frequency $_{01}$, relaxation time T_1 and the inverse of microwave width

 1 are plotted versus current bias for the two di erent applied uxes $_{\rm b1}$ (close to $_{\rm b0}$) and $_{\rm b2}$ shown in Fig. 2. $_{01}$, T_1 and $^{-1}$ decreases as $I_{\rm b}$ gets closer to $I_{\rm c}$. For these two applied uxes, the $_{01}$ dependence ts perfectly the sem iclassical form ulas for a cubic potential [17] using the same SQUID electrical parameters as those extracted from escape m easurem ents.

The depolarization rate T_1^{-1} is given by the sum $T_1^{-1} = R_R^{-1} + E_R^{-1}$ of the relaxation R_R^{-1} and the excitation E_R^{-1} rates. These two rates are calculated using Ferm i golden rule. At low temperature, excitation can be neglected and R_R^{-1} reads:

$$_{R} = \frac{r_{I}^{2}()}{4C_{0}h_{01}}S_{I}(_{01}) + \frac{r^{2}()}{L_{s}^{2}C_{0}h_{01}}S_{I}(_{01}):$$

Neglecting the high frequency part of the ux noise, one obtains $T_1 = 2R_e$ ($_{01}$) $C_0=r_1^2$ () where R_e ($_{01}$) = (2 L_{oc} $_{01}$) $^2=R_g$ ($_{01}$). R_g () = R_s is the high frequency resistance of the gold capacitor where $R_s = \frac{P}{0} \frac{1}{0 g}$ is the surface resistance and is a dimensionless geometrical parameter. The T_1 versus I_b dependence is well tted with = 200 as the only adjustable parameter (Fig. 4 b). This value is the right order of magnitude for the geom -

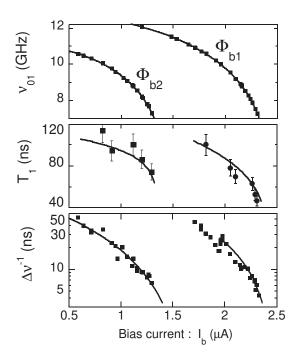


FIG.4: Resonant transition frequency (a), relaxation time (b) and m icrowave width (c) as function of bias current at $_{\rm bl}$ = 0:117 $_0$ and $_{\rm b2}$ = 0:368 $_0$ respectively right and left curves. Symbols correspond to experiments and continuous line to m odel predictions.

etry of the gold capacitor.

R elaxation alone is too weak to explain the value of and "pure" dephasing also contribute to the linew idths. F inst, we consider the time evolution of the reduced density matrix in the basis fjli; jlig in the absence of MW. The linear coupling to noise sources induces a time decay of the amplitude $f_{\rm coh}$ (t) of the coherence term s. Since current and ux noises are independent, $f_{\rm coh}$ (t) is factorized as $f_{\rm coh}$ (t) = $f_{\rm I}$ (t) f (t) exp ($2t=T_{\rm I}$) where $f_{\rm I}$ (t) and f (t) are respectively the "pure" dephasing contributions due to current and ux noises.

The current contribution is given by the well-known gaussian noise formula [10, 18]: $f_{I}(t) = \exp -\frac{1}{2}t^{2}$

 $2 \frac{(0-1)}{(0-1)} e^{2R_{+1}} dS_{I}() sinc(t), where (0-1) = (0-1) is extracted directly from the slope of the experimental curve of Fig. 4.a. We neglect ux noise contributions with frequencies higher than 20kH z. Since the acquisition time of absorption spectra and escape measurements are similar, the SQUID undergoes the same RMS ux uctuations in the two experiments. In these conditions, f(t) takes the simple gaussian form : f(t) = exp = \frac{1}{2}t^{2}$

 $2 \frac{\frac{\theta}{\theta} - 01}{\frac{\theta}{\theta} - b}^2 \frac{2}{L_F}$. ($\theta - 01 = \theta - b$) was computed using the known electrical parameters of the SQUID [19].

W ithin linear response, the shape of the resonance curve is proportional to the Fourier transform (FT) of $f_{\rm coh}$ (t). Resonance curves in Fig. 3.a and 3.b are $\,$ t-Pesc / FTff_{coh}g(ted using P_{esc} 01) (continuous line). Our model explains perfectly the shape of the experim ental curves. In Fig. 4.c, the theoretical width extracted from the curve $FTff_{coh}g()$ is in very good agreem ent with experim ental data without free param eter. W hen I_b gets close to I_c , the partial derivatives $(0 \quad 01 = 0 I_b)$ and $(0 \quad 01 = 0 \quad b)$ increase: the noise sensitivity increases and broadens. For bias points corresponding to $_{b2}$, the width is due to current and ux noise. For a bias ux equal to b1, the e ect of ux noise is small and the width is dom inated by current noise. At this ux, for I_b < 1:95 A, our model predicts satellite resonances around 01 which are not observed. Other noise mechanism may blur the predicted satellite peaks.

In conclusion, we have shown how the ux and current noise present in this controlled quantum circuit can be separately identi ed. W e m easured the decoherence times at low m icrowave power where the quantum circuit can be reduced to a two level system. A nalyzing the coupling of the SQUID to the known noise sources, the m easured relaxation times and the resonance width can be fully understood.

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